CLAIMS:

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1. An ion mobility spectrometer comprising an ionizer, an ion filter, and an ion detector;

wherein the ion filter defines at least one ion channel along which ions may pass from the ionizer to the ion detector; and

wherein the ion channel is defined by a plurality of conductive layers separated along the length of the channel by at least one non-conductive layer;

the spectrometer further comprising control means for applying electric potential to the conductive layers of the ion channel.

- 2. The spectrometer of claim 1, further comprising a deflector, for deflecting ions away from the ionizer and towards the ion detector.
- 3. The spectrometer of claim 1 or claim 2, wherein the control means allows the application of a time-varying electric potential to the conductive layers.
 - 4. The spectrometer of claim 3, wherein the electric potential is oscillating.
- 5. The spectrometer of claim 3 or 4, wherein the electric potential is timevarying in an asymmetric manner.
 - 6. The spectrometer of any preceding claim, wherein the control means allows the electric potential to be selectively varied.
 - 7. The spectrometer of any preceding claim, wherein the filter comprises a plurality of ion channels.
- 8. The spectrometer of claim 7, wherein the conductive layers form electrodes and the ion channels are defined at either end by apertures in said electrodes.

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9. The spectrometer of any preceding claim, wherein the filter comprises two or more interdigitated electrode arrays, each array having a plurality of channel-defining slots.

- 10. The spectrometer of any preceding claim, wherein the filter comprises a resistive or semiconductive substrate on which the conductive layers and non-conductive layer are provided.
 - 11. The spectrometer of claim 10, wherein the substrate is the ion detector.

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- 12. The spectrometer of any preceding claim, wherein two conductive layers are provided.
- 13. The spectrometer of any preceding claim, wherein two non-conductive layers are provided.
 - 14. The spectrometer of any preceding claim, wherein the filter has the structure C-NC-C-NC, where C and NC represent conductive and non-conductive layers respectively.

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- 15. The spectrometer of claim 14, wherein the filter further includes a substrate.
- 16. The spectrometer of any of claims 1 to 13, wherein the filter has the structure C-NC-substrate-NC-C, where C and NC represent conductive and non-conductive layers respectively.
 - 17. The spectrometer of any preceding claim, wherein the spectrometer comprises a plurality of functional layers.
- 18. The spectrometer of any preceding claim further comprising a semipermeable membrane.

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19. The spectrometer of claim 18 wherein the membrane comprises a heating element.

- 20. The spectrometer of claim 18 or 19 wherein the membrane is in the form of an inlet tube.
 - 21. The spectrometer of any preceding claim comprising a standard.

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- 22. The spectrometer of any preceding claim comprising multiple ion filters.
- 23. The spectrometer of any preceding claim comprising multiple ion detectors.
- 24. The spectrometer of any preceding claim further comprising means for generating a gas flow through the spectrometer.
- 25. The spectrometer of claim 24 wherein the gas flow is a counterflow against the direction of movement of ions.
- 26. The spectrometer of any preceding claim further comprising means for heating the filter.
 - 27. The spectrometer of claim 26 wherein the heating means comprises a substrate which is heated by Joule effect heating.
- 28. The spectrometer of any preceding claim wherein the ion channel includes inert conductive particles located on the walls of the channel along its length.
 - 29. The spectrometer of any preceding claim wherein the ion filter comprises a wafer-like form.
 - 30. The spectrometer of any of claims 1 to 28 wherein the ion filter comprises a plurality of stacked planar layers.

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- 31. The spectrometer of any preceding claim wherein the ion channel is curved or serpentine.
- 32. A spectrometer according to any preceding claim when coupled to one or more other detection or analysis devices.
 - 33. The spectrometer of any preceding claim further comprising control means for operating the spectrometer periodically to sample at intervals.
- 34. The spectrometer of any preceding claim wherein the ion detector comprises an electrode coupled to a capacitor which is periodically discharged.
 - 35. A method of analysing a sample, the method comprising the steps of:

ionising a sample to generate ions adjacent an ion channel, the ion channel being defined by a plurality of conductive layers separated along the length of the channel by at least one non-conductive layer;

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biasing the ions such that, in the absence of other forces, they would tend to travel along the ion channel;

applying electric potential to the conductive layers, such that an electric field is established within the ion channel; and

detecting generated ions which have passed through the ion channel.

- 36. An ion filter for use in an ion mobility spectrometer, the filter defining at least one ion channel along which ions may pass, wherein the ion channel is defined by a plurality of conductive layers separated along the length of the channel by at least one non-conductive layer.
- 37. The filter of claim 36, having the structure C-NC-C-NC, where C and NC represent conductive and non-conductive layers respectively.
- 38. The filter of claim 36, having the structure C-NC-substrate-NC-C, where C and NC represent conductive and non-conductive layers respectively.

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39. A method of manufacturing an ion mobility spectrometer, the method comprising the steps of:

providing a generally planar resistive substrate having thereon a plurality of conductive layers separated by at least one non-conductive layer;

patterning the substrate to provide a filter comprising two or more interdigitated electrode arrays defining a plurality of ion channels themselves defined by a plurality of conductive layers separated along the length of the channel by at least one non-conductive layer; and

attaching said filter on one face to a generally planar ionisation layer comprising means for ionising an analyte.

40. An ion mobility spectrometer comprising an ionizer, an ion filter, and an ion detector; wherein the ion filter defines at least one ion channel along which ions may pass from the ionizer to the ion detector; and wherein the ion filter comprises a plurality of electrodes disposed proximate the ion channel; the spectrometer further comprising electrode control means for controlling the electrodes such that a first drive electric field is generated along the length of the ion channel, and a second transverse electric field is generated orthogonal to the first; and additional control means for operating the spectrometer periodically to sample at intervals.

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41. An ion filter for use in a spectrometer such as an ion mobility spectrometer, the filter comprising a pair of interdigitated electrodes defining a plurality of ion channels along which ions may pass.